Onsemi

MOSFET – P-Channel, QFET[®]

-60 V, -30 A, 26 mΩ

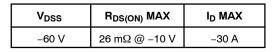
FQPF47P06, FQPF47P06YDTU

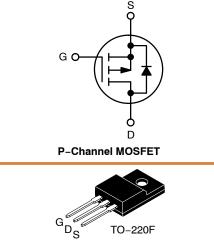
Description

This P-Channel enhancement mode power MOSFET is produced using onsemi's proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, audio amplifier, DC motor control, and variable switching power applications.

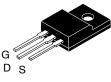
Features

- $-30 \text{ A}, -60 \text{ V}, \text{R}_{\text{DS(on)}} = 26 \text{ m}\Omega \text{ (Max.)} @ \text{V}_{\text{GS}} = -10 \text{ V}, \text{I}_{\text{D}} = -15 \text{ A}$
- Low Gate Charge (Typ. 84 nC)
- Low Crss (Typ. 320 pF)
- 100% Avalanche Tested
- 175°C Maximum Junction Temperature Rating



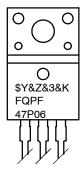


TO-220 Fullpack, 3-Lead / TO-220F-3SG CASE 221AT



TO-220-3LD LF CASE 340BJ

MARKING DIAGRAM



\$Y	= onsemi Logo
&Z	= Assembly Plant Co

&3

- = Assembly Plant Code
- = 3-Digit Plant Code
- = 2-Digits Lot Run Traceability Code &K
- FQPF47P06 = Specific Device Code

ORDERING INFORMATION

Device	Package	Shipping
FQPF47P06	TO-220-3 (Pb-Free)	1000 Units / Tube
FQPF47P06YDTU	TO-220-3 (Pb-Free)	800 Units / Tube

Symbol	Parameter		FQPF47P06 / FQPF47P06YDTU	Unit
V _{DSS}	Drain-Source Voltage		-60	V
I _D	Drain Current	– Continuous (T _C = 25°C)	-30	Α
		– Continuous (T _C = 100°C)	-21.2	А
I _{DM}	Drain Current (Note 1)	– Pulsed	-120	А
V _{GSS}	Gate-Source Voltage		+ 25	V
E _{AS}	Single Pulsed Avalanche Energy (Note 2)		820	mJ
I _{AR}	Avalanche Current (Note 1)		-30	А
E _{AR}	Repetitive Avalanche Energy (Note	e 1)	6.2	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3	3)	-7.0	V/ns
PD	Power Dissipation (T _C = 25°C)		62	W
		- Derate above 25°C	0.41	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +175	°C
ΤL	Maximum Lead Temperature for So 1/8" from Case for 5 Seconds	oldering Purposes,	300	°C

ABSOLUTE MAXIMUM RATINGS (T_C = 25°C unless otherwise specified)

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected. 1. Repetitive Rating: Pulse width limited by maximum junction temperature 2. L = 1.06 mH, $I_{AS} = -30 \text{ A}$, $V_{DD} = -25 \text{ V}$, $R_G = 25 \Omega$, Starting $T_J = 25^{\circ}\text{C}$ 3. $I_{SD} \leq -47 \text{ A}$, di/dt $\leq 300\text{A}/\mu\text{s}$, $V_{DD} \leq \text{BV}_{DSS}$, Starting $T_J = 25^{\circ}\text{C}$

THERMAL CHARACTERISTICS

Symbol	Characteristic	Тур	Max	Unit
$R_{ ext{ heta}JC}$	Thermal Resistance, Junction-to-Case	-	2.42	°C/W
$R_{ hetaJA}$	Thermal Resistance, Junction-to-Ambient	-	62.5	°C/W

ELECTRICAL CHARACTERISTICS (T_C = 25° C unless otherwise noted)

Symbol	Parameter	Test Condition	Min	Тур	Max	Unit
OFF CHAR	RACTERISTICS					
BV _{DSS}	Drain-Source Breakdown Voltage	V_{GS} = 0 V, I_D = -250 μ A	-60		-	V
$\begin{array}{c} \Delta \text{BV}_{\text{DSS}} \\ / \Delta \text{T}_{\text{J}} \end{array}$	Breakdown Voltage Temperature Coefficient	$I_D = -250 \ \mu A$, Referenced to $25^{\circ}C$	-	-0.06	-	V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V_{DS} = -60 V, V_{GS} = 0 V	-	-	-1	μA
		$V_{DS} = -48$ V, $T_{C} = 150^{\circ}C$	-	-	-10	μA
I _{GSSF}	Gate-Body Leakage Current, Forward	V_{GS} = -25 V, V_{DS} = 0 V	-	-	-100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = 25 \text{ V}, \text{ V}_{DS} = 0 \text{ V}$	-	-	100	nA
ON CHAR	ACTERISTICS					
V _{GS(th})	Gate Threshold Voltage	$V_{DS}=V_{GS},\ I_{D}=-250\ \mu A$	-2.0	-	-4.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	$V_{GS} = -10 \text{ V}, \text{ I}_{D} = -15 \text{ A}$	-	0.021	0.026	Ω
9 _{FS}	Forward Transconductance	$V_{DS} = -30 \text{ V}, I_D = -15 \text{ A} \text{ (Note 4)}$	-	19	-	S
DYNAMIC	CHARACTERISTICS	•				
C _{iss}	Input Capacitance	V_{DS} = -25 V, V_{GS} = 0 V, f = 1.0 MHz	-	2800	3600	pF
C _{oss}	Output Capacitance	7	-	1300	1700	pF
C _{rss}	Reverse Transfer Capacitance	7	-	320	420	pF
SWITCHIN	G CHARACTERISTICS	•				
t _{d(on)}	Turn-On Delay Time	V_{DD} = -30 V, I_D = -23.5 A, R_G = 25 Ω	-	50	110	ns
t _r	Turn–On Rise Time	— (Note 4, 5) —	-	450	910	ns
t _{d(off)}	Turn-Off Delay Time		-	100	210	ns
t _f	Turn-Off Fall Time		-	195	400	ns
Qg	Total Gate Charge	$V_{DS} = -48$ V, $I_D = -47$ A, $V_{GS} = -10$ V	-	84	110	nC
Q _{gs}	Gate-Source Charge	(Note 4, 5)	-	18	-	nC
Q _{gd}	Gate-Drain Charge	7	-	44	-	nC
DRAIN-SC	OURCE DIODE CHARACTERISTICS AND MAX	IMUM RATING				
I _S	Maximum Continuous Drain-Source Diode Forward Current		-	-	-30	Α
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current		_	-	-120	Α
V_{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, \text{ I}_{S} = -30 \text{ A}$	-	-	-4.0	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, \text{ I}_S = -47 \text{ A},$ $dI_F / dt = 100 \text{ A}/\mu \text{s} \text{ (Note 4)}$	-	130	-	ns
Qrr	Reverse Recovery Charge		_	0.55	_	uC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions. 4. Pulse Test: Pulse width \leq 300 μ s, Duty cycle \leq 2%

0.55

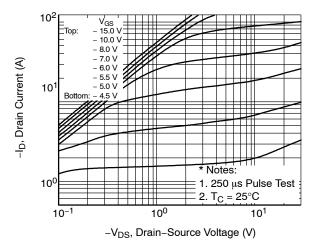
μC

Reverse Recovery Charge

Q_{rr}

5. Essentially independent of operating temperature

TYPICAL CHARACTERISTICS





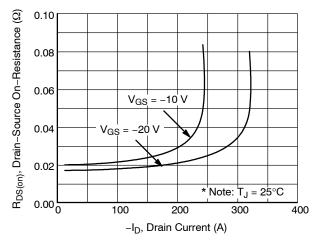


Figure 3. On–Resistance Variation vs. Drain Current and Gate Voltage

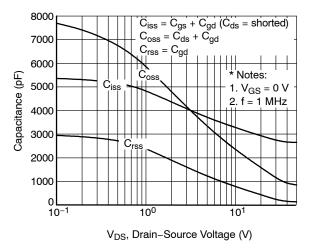
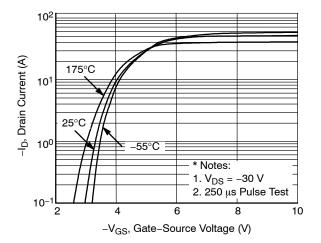


Figure 5. Capacitance Characteristics





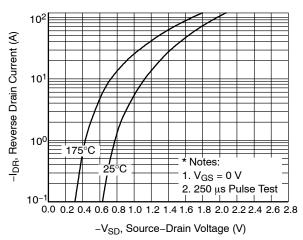


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

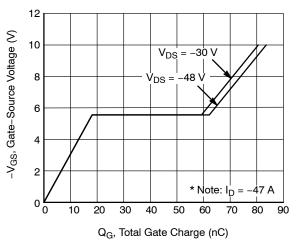
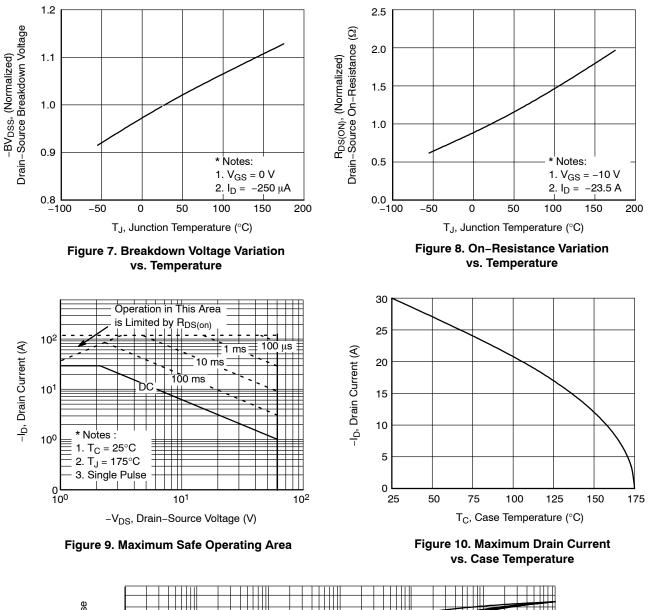


Figure 6. Gate Charge Characteristics

TYPICAL CHARACTERISTICS (Continued)



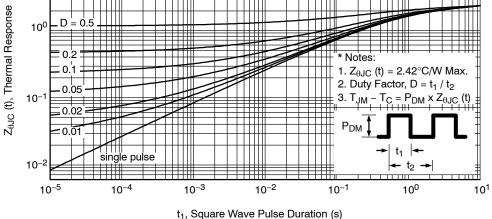


Figure 11. Transient Thermal Response Curve

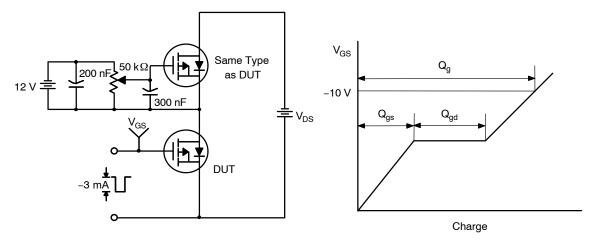


Figure 12. Gate Charge Test Circuit & Waveform

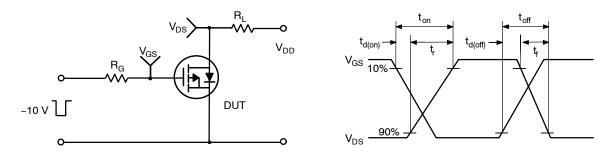


Figure 13. Resistive Switching Test Circuit & Waveforms

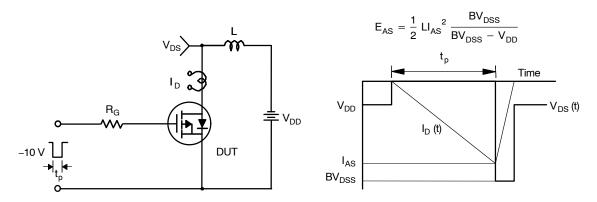


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms

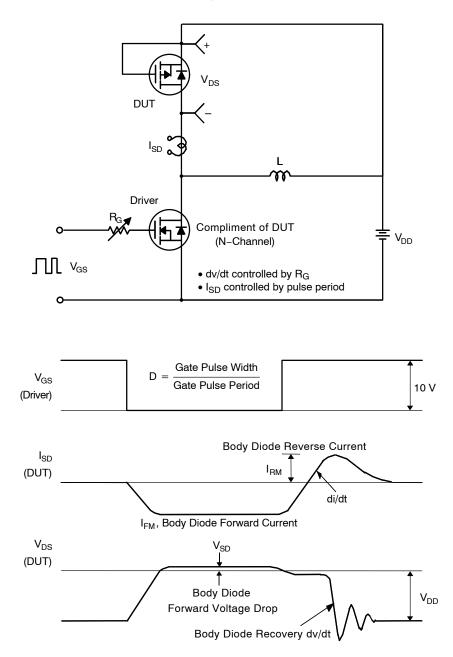
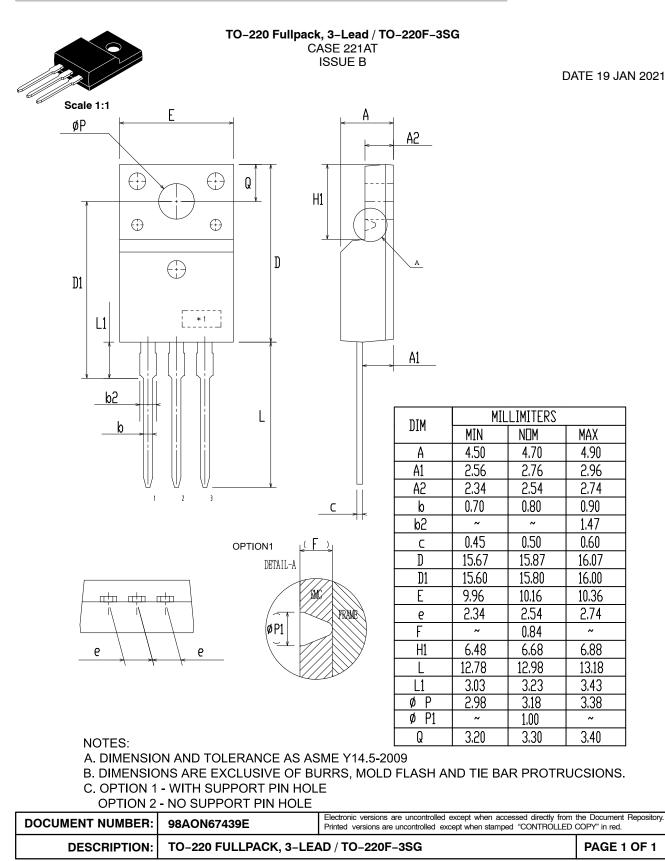


Figure 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms

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TO-220-3LD LF CASE 340BJ ISSUE O DATE 31 AUG 2016 2.74 2.34 10.36 В А Β 9.96 3.28 Ø 7.00)-3.08 3.40 -(0.70) 3.20 6.88 6.48 + 1 X 45° 16.07 ΈB 15.67 16.00 15.60 (R0.30) 3 1 R0.30) 2.96 2.561.47 MAX 10.45 10.00 ∕B∖ ∕B∖ (2.14)-9.45 9.00 0.90 0.70 ⊕ 0.50∭ A 0.60 <u>B</u> 0.45 B 4.00 MIN -6.00 2.54 ́В∖ 2.54 4.00 NOTES: A. EXCEPT WHERE NOTED CONFORMS TO EIAJ SC91A. B DOES NOT COMPLY EIAJ STD. VALUE. C. ALL DIMENSIONS ARE IN MILLIMETERS. D. DIMENSIONS ARE EXCLUSIVE OF BURRS. 4.90 ∕B∖ ́B∖ 4.50 MOLD FLASH AND TIE BAR PROTRUSIÓNS. E. DIMENSION AND TOLERANCE AS PER ASME Y14.5-1994.

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 DESCRIPTION:
 TO-220-3LD LF
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